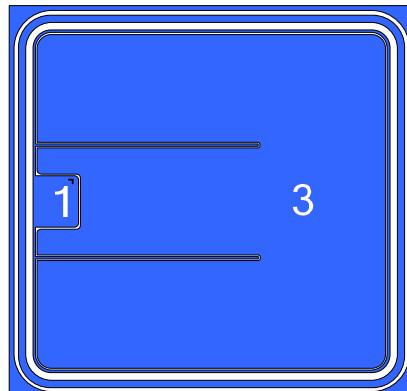


## 3VD395650YL HIGH VOLTAGE MOSFET CHIPS

### DESCRIPTION

- 3VD395650YL is a High voltage N-Channel enhancement mode power MOS-FET chip fabricated in advanced silicon epitaxial planar technology;
- Advanced termination scheme to provide enhanced voltage-blocking capability;
- Avalanche Energy Specified;
- Source-to-Drain Diode Recovery Time Comparable to a Discrete Fast Recovery Diode;
- The chips may packaged in TO-220 type and the typical equivalent product is 7N65;
- The packaged product is widely used in AC-DC power suppliers, DC-DC converters and H-bridge PWM motor drivers;
- Die size: 4.04mm\*3.88mm;
- Chip Thickness: 300±20μm;
- Top metal: Al, Backside Metal: Ag.



1-Gate PAD 3-Source PAD

**CHIP TOPOGRAPHY**

### ABSOLUTE MAXIMUM RATINGS ( $T_{amb}=25^{\circ}C$ )

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	V <sub>DS</sub>	650	V
Gate-Source Voltage	V <sub>G</sub>	±30	V
Drain Current	I <sub>D</sub>	7.0	A
Power Dissipation (TO-220 Package)	P <sub>D</sub>	147	W
Operation Junction Temperature	T <sub>J</sub>	-55~+150	°C
Storage Temperature	T <sub>stg</sub>	-55~+150	°C

### ELECTRICAL CHARACTERISTICS ( $T_{amb}=25^{\circ}C$ )

Parameter	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Drain -Source Breakdown Voltage	BVDSS	V <sub>G</sub> =0V, I <sub>D</sub> =250μA	650	-	-	V
Gate Threshold Voltage	V <sub>TH</sub>	V <sub>G</sub> = V <sub>DS</sub> , I <sub>D</sub> =250μA	2.0	-	4.0	V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =650V, V <sub>G</sub> =0V	-	-	1.0	μA
Static Drain- Source On State Resistance	R <sub>DSS(on)</sub>	V <sub>G</sub> =10V, I <sub>D</sub> =3.5A	-	-	1.4	Ω
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>G</sub> =±30V, V <sub>DS</sub> =0V	-	-	±100	nA
Source-Drain Diode Forward on Voltage	V <sub>FSD</sub>	I <sub>S</sub> =7.0A, V <sub>G</sub> =0V	-	-	1.4	V